

Tamm surface resonances in very low energy electron scattering from clean metal surfaces

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Very low-energy features which occur in electron reflectivities from clean fcc metal (111) surfaces have been subject to a number of interpretations. Here we analyse the feature near 19.8 eV on Cu(111) at normal incidence and find that it is due to resonant scattering at the rise of the muffin-tin average interstitial potential between atomic layers on approach to the surface from the bulk. This new mechanism corresponds to a Tamm-type surface resonance which is very different in formation to the usual Shockley and Rydberg resonances and explains all features in a systematic way.

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The copper (111) surface is of special interest because it has a band gap between the Fermi level and vacuum level where a Shockley surface state exists. Adsorbed alkali metals on this surface produce interface states which also lie in this region. These states form a quasi 2D free-electron gas within a quantum well and it has been suggested that such systems can be used for device application at room temperature [1]. It is therefore important that properties of the clean metal surface are completely determined. These can be studied by photoemission (PE), inverse photoemission (IPE) spectroscopies and other techniques which give (mostly) below vacuum energy level data. Above-vacuum energy-level data can be found from very low energy electron scattering spectroscopies such as very low energy electron diffraction (VLEED), low energy electron microscopy (LEEM) and target current spectroscopy (TCS). Both regions can be analyzed theoretically by a layer-by-layer KKR scattering method [2] and properties determined from both energy regions must exhibit a smooth continuation over the whole energy range. This approach effectively provides an expanded data base from which to unravel the complicated surface properties, many of which are expected to have significant energy and momentum variation. Information obtained from the higher energy region also has relevance for analyzing the below-vacuum region.

Here we analyze VLEED and LEEM data on Cu(111). The experimental data at normal incidence has a peak at ~ 20 eV which has not been easy to explain. It has variously been attributed to a band structure effect [3], a sub-threshold effect [4] and anisotropic inelastic scattering [5]. Similar features are also present for other (111) metal surfaces [3]. VLEED and LEEM data may have been under-utilized because of the difficulty in systematically accounting for all the features. This is unfortunate because it is very sensitive to surface scattering potentials and electron self-energy including their energy and momentum variation. It is also more sensitive to the vertical position of surface atoms than LEED which is

performed at energies higher than ~ 40 eV.

Shockley and Rydberg states and resonances have been detected in below-vacuum PE and IPE experimental data and resonances in above-vacuum VLEED, LEEM and TCS data. Historically surface states (and resonances) have been labeled as Tamm-type and Shockley-type although in some contexts there is no sharp distinction. In a scattering approach, the surface state can be labeled a Shockley type if an essential element in its formation is the shape of the surface barrier in the vacuum beyond the top row of atoms. (They have also been called crystal-induced surface barrier states in this context). Rydberg states arise from the image potential tail of the surface barrier beyond the top row of atoms and are also called image surface barrier states. In this context a Tamm surface state/resonance could be defined as one which arises from change in the 3D periodicity of the crystal near the surface but is not of the Shockley type as defined above and not due to adsorbed foreign surface atoms. In a scattering picture, the Shockley and Rydberg states/resonances arise because of standing waves forming at some energies in the potential well consisting of the crystal on one side and the rise of the surface barrier to the vacuum on the other.

With the vacuum emergence of the $\{01\}, \{10\}$ beams at 30.7 eV for Cu (111) at normal incidence and an expected crystal inner potential of ~ 13 eV [4], the 20 eV peak lies in the energy range between the crystal and vacuum emergence of the above non-specular beams. In this case scattering of these beams at the surface barrier can produce Shockley resonances. If this situation were the case, the 20 eV peak would give important information about the form of the surface barrier near where it joins to the crystal which has consequences for the determination of other barrier properties. Such a low-energy lying Shockley-type resonance has not been identified to date.

This possibility has been examined but the 20 eV peak width, height and Bragg-peak separation could not be reproduced by this mechanism for realistic values of elec-

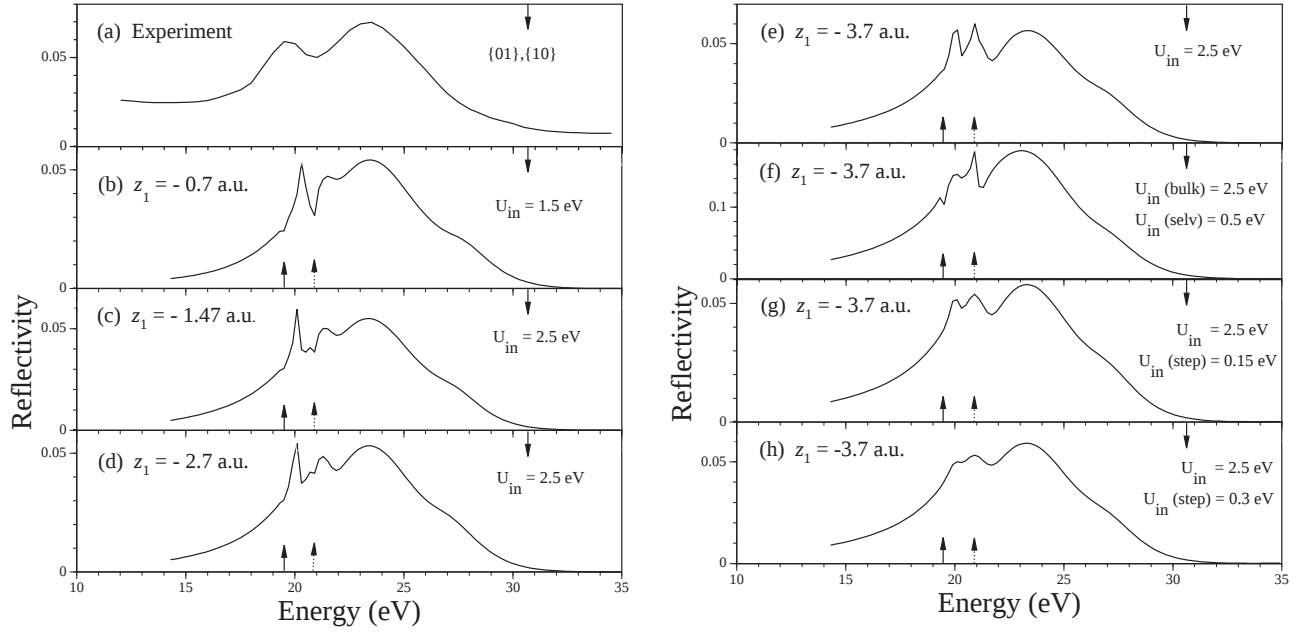


FIG. 3: Reflectivity of 00 beam on Cu(111) at normal incidence. Frame (a) is the experimental result of Ref. 5 with energy step 0.5 eV. Frames (b) $\rightarrow$ (h) are calculated profiles with $U_o = 11.15$ eV and $U_{in} = 2.5$ eV in all layers except frame (f) which has $U_{in} = 0.5$ eV in the top atomic layer. Symbols are described in Fig. 1. In all cases an interlayer step of height $U_1 = 1.4$ eV is placed between the top layer and the next layer at positions z_1 from the centre of the second row of atoms at the surface, as indicated on the diagrams. The surface barrier height is 9.75 eV, the crystal temperature is 300 K and Debye temperature 315 K. Downward/upward arrows are the same as in Fig. 1. Dashed upward arrows indicate crystal emergence energy of $\{01\}, \{10\}$ beams in the top atomic layer. Frames (g) and (h) have inelastic absorption at the interlayer step as described in the text.

a.u. The interlayer rise in potential is modeled in these calculations by a simple step potential placed between $z = 0$ and -3.9438 a.u. From higher energy LEED analyses on Cu(111) the surface atomic layers have not been found to deviated significantly from their bulk positions [4]. From the position $z = -3.9438$ a.u. there is a further rise in potential representing the surface barrier of height U_2 . The total rise in potential from the bulk muffin-tin zero to vacuum level is $U_1 + U_2 = U_0 = 11.15$ eV in the calculations shown here.

Wave vectors of the wave functions corresponding to beam v in the three regions bulk, selvedge and vacuum are represented by $\mathbf{k}_v^\pm$, $\bar{\mathbf{k}}_v^\pm$ and $\mathbf{K}_v^\pm$ respectively after the notation of McRae [9]. For the interlayer step, the reflection and transmission coefficients are

$$\rho_S(\mathbf{k}_v^+ \mathbf{k}_v^-) = \frac{(k_v^\perp - \bar{k}_v^\perp)}{(k_v^\perp + \bar{k}_v^\perp)} \exp[-2iz_1 k_v^\perp]. \quad (1a)$$

$$\tau_S(\bar{\mathbf{k}}_v^- \mathbf{k}_v^-) = \frac{2k_v^\perp}{(k_v^\perp + \bar{k}_v^\perp)} \exp[iz_1(\bar{k}_v^\perp - k_v^\perp)]. \quad (1b)$$

$$\rho_S(\bar{\mathbf{k}}_v^- \bar{\mathbf{k}}_v^+) = \frac{(\bar{k}_v^\perp - k_v^\perp)}{(\bar{k}_v^\perp + k_v^\perp)} \exp[2iz_1 \bar{k}_v^\perp]. \quad (1c)$$

$$\tau_S(\mathbf{k}_v^+ \bar{\mathbf{k}}_v^+) = \frac{2\bar{k}_v^\perp}{(\bar{k}_v^\perp + k_v^\perp)} \exp[iz_1(-k_v^\perp + \bar{k}_v^\perp)]. \quad (1d)$$

where $k_v^\perp$, $\bar{k}_v^\perp$ are the perpendicular components of the

corresponding wave vectors and z_1 is the position (with respect to the origin) of the potential step. This sharp step overestimates above-step reflections but the aim is to keep the model as simple as possible at this stage and easily reproducible by others. The ρ_S and τ_S were used to calculate a transfer matrix $\mathbf{Q}_2$ for this step scattering layer according to Eq. (14) of McRae [9]. Similarly transfer matrices for the top atomic selvedge layer $\mathbf{Q}_1$ and for the surface barrier layer $\mathbf{Q}_0$ were calculated, giving a selvedge scattering matrix $\mathbf{X}$ where

$$\mathbf{X} = \mathbf{Q}_2 \cdot \mathbf{Q}_1 \cdot \mathbf{Q}_0. \quad (2)$$

The selvedge scattering matrix $\mathbf{X}$ was combined with the bulk crystal scattering matrix $\mathbf{M}$ using Eq. (35) of McRae [9]. In order to keep the model as uncomplicated as possible, the phase shifts for the top atomic selvedge layer were kept the same as the bulk. The bulk isotropic inelastic scattering potential $U_{in}(\text{bulk})$ was 2.5 eV and for the selvedge atom layer $U_{in}(\text{selv})$ was chosen from 0.5 to 2.5 eV. Different heights U_1 of the interlayer step (and barrier height U_2) were tried.

Fig. 3 shows the results of our calculation for interlayer step positions from $z_1 = -0.7$ to -3.7 a.u. with $U_1 = 1.4$ eV. In frames (b) to (d), no inelastic scattering was included for the step layer, i.e. the normal components of the wave vectors in Eq. (1) had no imaginary components. This of course overestimates the effects but allows

one to see the possibilities. Firstly, the value of inelastic scattering in the seldge top layer, $U_{\text{in}}(\text{selv})$, has some effect on the fine structure features but for this simple model, optimization of such parameters was not considered appropriate at this stage. In comparison with the reflectivity without the interlayer step as seen in frame (a) of Fig. 1, we see that a peak appears near 20 eV and moves down in energy from 20.3 to 20 eV as $|z_1|$ increases. The six $\{01\}, \{10\}$ beams emerge in the bulk crystal layers at 19.5 eV and in the seldge top atomic layer at 20.9 eV (with respect to the vacuum level). The $\{01\}, \{10\}$ beams from the bulk are propagating and incident on the step in a direction towards the surface in the energy range above 19.5 eV. The $\{01\}, \{10\}$ beams in the top atomic layer are incident on the step in a direction away from the surface and are evanescent until 20.9 eV when they become propagating. Multiple reflections and transmissions in both directions give rise to the $\{01\}, \{10\}$ beams becoming incident on the bulk atomic layers and seldge atomic layers with phases and amplitudes different from what occurs without the step. At certain energies, standing waves may form which correspond, in a scattering picture, to what historically has been called Tamm surface resonances. The non-specular scattering at atomic layers leaks some flux into the 00 beam. Above step-height reflections may be exaggerated here but some will also occur for a smoother interlayer potential rise.

In this model, inelastic scattering in the whole volume of the seldge and substrate regions already has been taken into account in the calculation of the bulk and atomic layer scattering matrices. Also inelastic scattering in the top bulk layer is likely to be different from that for lower positioned layers. It is difficult for a model based on the analytical reflections coefficients in Eq. (1) to ascribe appropriate inelastic scattering from events associated with the step only. Changes in the isotropic-layer inelastic scattering potentials on approach to the surface are unknown quantities at this stage. Hence for this model we have reduced the intensity of the interlayer step features somewhat arbitrarily through the wave vectors in Eq. (1) by adding an inelastic scattering potential, $U_{\text{in}}(\text{step})$, of 0.3 eV and 0.15 eV. This simulates how the features change with inelastic scattering. We see in frame (e) of Fig. 3 that the structure appears to be of the same form as seen in the experimental data including its energy width and separation from the Bragg peak. Resolution of any fine structure features would also be lost in most experimental set-ups because of beam width and energy broadening. With exaggerated above-step features the model used here would not be expected to exactly reproduce the experimental result, but the origin of the feature can be determined.

In conclusion we have found the following: (a) For normal incidence electron reflectivity from Cu(111), a peak near 20 eV with the given experimental width, height and Bragg-peak separation could not be produced from a surface barrier with image origin, z_0 , located in a realistic position and for inelastic scattering potential, U_{in} , of realistic value; the peak is not due to a Shockley-type surface barrier resonance. (b) The 20 eV peak is due to resonant scattering at the rise in the average interstitial potential between atomic layers on approach to the surface. It is therefore a Tamm-type surface resonance. This type of surface resonance has not been identified before in VLEED, LEEM etc. It is also likely to account for similar features in other clean metal (111) surfaces. (c) The interlayer rise in potential may only produce surface resonances when they fall in the energy range of a surface-projected bulk band pseudo-gap (Bragg peak) in VLEED and related spectroscopies. (d) Even when the condition in (c) above is not fulfilled, the rise in potential before the top atomic layer will change the value of the height of the surface barrier. This value affects the determination of barrier features such as image origin position, saturation etc, for both below vacuum level spectroscopies (PE, IPE) and those above (VLEED, LEEM, TCS). (e) All of the features in VLEED (0 - 40 eV) may now be accounted for in a systematic way if, (i) scattering at a realistic image surface barrier, and (ii) scattering at the interlayer rise in interstitial muffin-tin potential between surface layers is included in the theoretical calculation of reflectivities. This would make VLEED and LEEM more widely used tools for unravelling surface properties in the future.

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